

**Search Notes**

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TAN X. DINH

Applicant(s)/Patent under  
Reexamination

HIGUCHI ET AL.

Art Unit

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**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

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Interference Search History Printout		11/28/2007	T.D

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
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